Search Notes

Application/Control No.	Applicant(s)/Patent unde Reexamination	er
10/568,947	MUTO ET AL.	
Examiner	Art Unit	
Hai H. Huyah	2747	

SEARCHED				
Class	Subclass	Date	Examiner	
123	399	4/4/2007	ннн	
123	350	4/4/2007	ннн	
123	90.11	4/4/2007	ннн	
123	90.15	4/4/2007	ннн	
123	90.16	4/4/2007	ннн	
123	90.17	4/4/2007	ННН	
123	568.11	4/4/2007	ннн	
123	568.14	4/4/2007	ннн	
73	117.3	4/4/2007	ННН	
73	118.2	4/4/2007	ннн	
701	106	4/4/2007	ннн	
701	110	4/4/2007	ннн	
701	115	4/4/2007	ннн	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East	4/4/2007	ннн